10/586581 IAP11 Rec'd PCT/PTO 19 JUL 2006

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of: Tsuguo FUKUDA et al.

Application Number: Not yet assigned

(§371 of international application No. PCT/JP2005/000696)

Filed: July 19, 2006

For: PROCESS FOR PRODUCING SINGLE CRYSTAL OF GALLIUM-

**CONTAINING NITRIDE** 

Attorney Docket Number:

062697

**Customer Number:** 

38834

## INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P. O. Box 1450 Alexandria, VA 22313-1450 July 19, 2006

Sir:

In compliance with 37 C.F.R. §1.56, Applicants direct the attention of the Patent and Trademark Office to the documents listed on the attached PTO/SB/08. A copy of each non- U.S. document is enclosed herewith as well as an International Search Report mailed April 5, 2005.

If there are any fees due in connection with the filing of this paper, please charge Deposit Account No. 50-2866.

Respectfully submitted,

WESTERMAN, HATTORI, DANIELS & ADRIAN, LLP

Sadao Kinashi

Attorney for Applicants Registration No. 48,075

Telephone: (202) 822-1100 Facsimile: (202) 822-1111

SK/mc

Enclosure: PTO/SB/08, Documents (8) & Int'l Search Report

1

## 10/586581

## IAP11 Rec'd PCT/PTO 19 JUL 2006

Combined Form PTO/SB/08A&B			Complete if Known			
Combined Form F 10/3B/00A&B				Application Number	Not yet assigned	
INFORMATION DISCLOSURE				Confirmation Number		
STATE	STATEMENT BY APPLICANT			Filing Date	July 19, 2006	
(use as many sheets as necessary)				First Named Inventor	Tsuguo FUKUDA et al.	
				Art Unit		
				Examiner Name		
Sheet	1	of	1	Attorney Docket Number	062697	

U.S. PATENT DOCUMENTS							
Examiner Initials*	Cita	Document Number		Publication Date			
	Cite No.1	Number	Kind Code <sup>2</sup> (if known)	MM-DD-YYYY	Name of Patentee or Applicant of Cited Document		
	1	US 6,273,948	Bl	8/14/2001	Porowski et al.		
	2	US 6,270,569	B1	8/7/2001	Shibata et al.		
	3	US 6,592,663	B1	7/15/2003	Sarayama et al.		
	4	US 5,363,799		11/15/1994	Yonehara et al.		
	5	US 2004/0144300	A1	7/29/2004	Kitaoka et al.		

FOREIGN PATENT DOCUMENTS							
Examiner Initials*	Cite No.1	Foreign Patent Document			Publication Date	Name of Patentee or	
		Country Code <sup>3</sup>	Number <sup>4</sup>	Kind Code <sup>5</sup> (if known)	MM-DD-YYYY	Applicant of Cited Document	Translation <sup>6</sup>
	6	JP	56-160400	A	12/10/1981	Matsushita Electrical Industrial Co., Ltd.	Abstract; Cited in ISR
	7	JP	1-132117	A	5/24/1989	Canon Inc.	Abstract; Cited in ISR; Corresponds to #4
	8	JР	2004-244307	A	9/2/2004	Matsushita Electric Industrial Co., Ltd.	Abstract; Cited in ISR; Corresponds to #5
	9	JP	2001-131741	A	5/15/2001	Sony Corp	Abstract; Cited in ISR

NON PATENT LITERATURE DOCUMENTS							
Examiner Cite Initials* No.1		Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city, and/or country where published.					
	10	M.K. KELLY et al., "Optical patterning of GaN films", Appl. Phys. Lett. 69 (12), 16 September 1996					
	11	W.S. WONG et al., "Fabrication of thin-film InGaN light-emitting diode membranes by laser lift-off", Applied Physics Letters, Volume 75, Number 10, 6 September 1999					
	12	TAKAYUKI INOUE et al., "Growth of Bulk GaN Single Crystals by the Pressure-Controlled", Central R&D Laboratory, Japan Energy Corporation, Faculty of Engineering, Yamaguchi University, May 15, 2000					
	13	S. POROWSKI et al., "Thermodynamical properties of III-V nitrides and crystal growth of", Journal of Crystal Growth 178 (1997) 174-188					
	14	International Search Report mailed April 5, 2005 of International Application PCT/JP2005/000696					

Examiner Signature	Date Considered	

<sup>\*</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<sup>&</sup>lt;sup>1</sup>Applicant's unique citation designation number (optional). <sup>2</sup>See Kind Codes of USPTO Patent Documents at www.uspto.gov, MPEP 901.04 or in the comment box of this document. <sup>3</sup> Enter Office that issued the document, by the two-letter code (WIPO Standard ST. 3). <sup>4</sup>For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup>Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. <sup>6</sup> Applicant is to indicate here if English language Translation is attached.